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## **Q0PACK Module**

The NXH80T120L2Q0S2/P2G is a power module containing a T-type neutral point clamped (NPC) three level inverter stage. The integrated field stop trench IGBTs and fast recovery diodes provide lower conduction losses and switching losses, enabling designers to achieve high efficiency and superior reliability.

#### **Features**

- Low Switching Loss
- Low V<sub>CESAT</sub>
- Compact 65.9 mm x 32.5 mm x 12 mm Package
- Thermistor
- Options with pre-applied thermal interface material (TIM) and without pre-applied TIM
- Options with solderable pins and press-fit pins

## **Typical Applications**

- Solar Inverter
- Uninterruptable Power Supplies

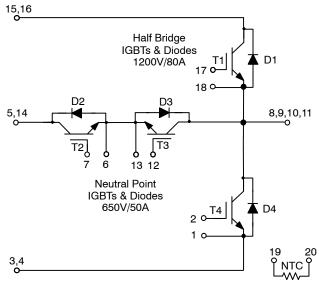
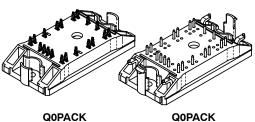


Figure 1. Schematic Diagram



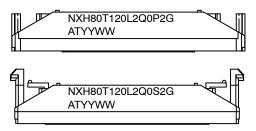
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Q0PACK CASE 180AA PRESS-FIT PINS Q0PACK CASE 180AB SOLDERABLE PINS

#### **MARKING DIAGRAMS**



NXH80T120L2Q0S2G = Specific Device Code

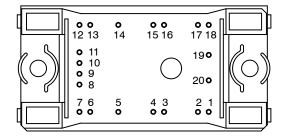
G = Pb-free Package

A = Assembly Site Code

T = Test Site Code

YYWW = Year and Work Week Code

#### **PIN ASSIGNMENTS**



## **ORDERING INFORMATION**

See detailed ordering and shipping information in the dimensions section on page 13 of this data sheet.

**Table 1. MAXIMUM RATINGS** 

Rating	Symbol	Value	Unit
HALF BRIDGE IGBT			
Collector-Emitter Voltage	V <sub>CES</sub>	1200	V
Gate-Emitter Voltage	V <sub>GE</sub>	±20	V
Continuous Collector Current @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	I <sub>C</sub>	67	Α
Pulsed Collector Current (T <sub>J</sub> = 175°C)	I <sub>Cpulse</sub>	201	Α
Maximum Power Dissipation @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	158	W
Short Circuit Withstand Time @ $V_{GE}$ = 15 V, $V_{CE}$ = 600 V, $T_{J} \leq 150^{\circ} C$	T <sub>sc</sub>	5	μs
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	150	°C
NEUTRAL POINT IGBT			
Collector-Emitter Voltage	V <sub>CES</sub>	600	V
Gate-Emitter Voltage	V <sub>GE</sub>	±20	V
Continuous Collector Current @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	I <sub>C</sub>	49	А
Pulsed Collector Current (T <sub>J</sub> = 175°C)	I <sub>Cpulse</sub>	147	А
Maximum Power Dissipation @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	86	W
Short Circuit Withstand Time @ $V_{GE}$ = 15 V, $V_{CE}$ = 400 V, $T_{J} \le 150^{\circ}C$	T <sub>sc</sub>	5	μs
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	150	°C
HALF BRIDGE DIODE			
Peak Repetitive Reverse Voltage	V <sub>RRM</sub>	1200	V
Continuous Forward Current @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	I <sub>F</sub>	28	А
Repetitive Peak Forward Current (T <sub>J</sub> = 175°C, t <sub>p</sub> limited by T <sub>Jmax</sub> )	I <sub>FRM</sub>	84	А
Maximum Power Dissipation @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	73	W
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	150	°C
NEUTRAL POINT DIODE			
Peak Repetitive Reverse Voltage	V <sub>RRM</sub>	650	V
Continuous Forward Current @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	l <sub>F</sub>	33	А
Repetitive Peak Forward Current (T <sub>J</sub> = 175°C, t <sub>p</sub> limited by T <sub>Jmax</sub> )	I <sub>FRM</sub>	99	А
Maximum Power Dissipation @ T <sub>h</sub> = 80°C (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	63	W
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	150	°C
THERMAL PROPERTIES			
Storage Temperature range	T <sub>stg</sub>	-40 to 125	°C
INSULATION PROPERTIES			
Isolation test voltage, t = 1 sec, 60 Hz	V <sub>is</sub>	3000	$V_{RMS}$
Creepage distance		12.7	mm

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## **Table 2. RECOMMENDED OPERATING RANGES**

Rating	Symbol	Min	Max	Unit
Module Operating Junction Temperature	T <sub>.1</sub>	-40	150	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

<sup>1.</sup> Refer to ELECTRICAL CHĂRACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.

Table 3. ELECTRICAL CHARACTERISTICS  $T_J = 25^{\circ}C$  unless otherwise noted

Parameter	Symbol	Min	Тур	Max	Unit	
HALF BRIDGE IGBT CHARACTERISTICS	·					
Collector-Emitter Cutoff Current	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V	I <sub>CES</sub>	_	_	300	μА
Collector-Emitter Saturation Voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 80 A, T <sub>J</sub> = 25°C	V <sub>CE(sat)</sub>	-	2.05	2.85	V
	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 80 A, T <sub>J</sub> = 150°C		-	2.10	-	1
Gate-Emitter Threshold Voltage	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 1.5 mA	V <sub>GE(TH)</sub>	-	5.45	6.4	V
Gate Leakage Current	V <sub>GE</sub> = 20 V, V <sub>CE</sub> = 0 V	I <sub>GES</sub>	=	-	300	nA
Turn-on Delay Time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	-	61	1	ns
Rise Time	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$	t <sub>r</sub>	=	28	-	1
Turn-off Delay Time	$V_{GE}$ = ±15V, $R_{G}$ = 4.7 $\Omega$	t <sub>d(off)</sub>	=	205	-	1
Fall Time	7	t <sub>f</sub>	=	41	_	1
Turn-on Switching Loss per Pulse	7	E <sub>on</sub>	=	550	-	μJ
Turn off Switching Loss per Pulse	7	E <sub>off</sub>	=	1100	-	1
Turn-on Delay Time	T <sub>J</sub> = 125°C	t <sub>d(on)</sub>	-	58	-	ns
Rise Time	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$	t <sub>r</sub>	=	30	-	1
Turn-off Delay Time	$V_{GE}$ = ±15 V, $R_{G}$ = 4.7 $\Omega$	t <sub>d(off)</sub>	=	230	_	1
Fall Time		t <sub>f</sub>	-	63	-	1
Turn-on Switching Loss per Pulse		E <sub>on</sub>	-	720	-	μJ
Turn off Switching Loss per Pulse		E <sub>off</sub>	_	1700	-	1
Input Capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 10 kHz	C <sub>ies</sub>	_	19400	-	pF
Output Capacitance	ance		-	400	=	
Reverse Transfer Capacitance		C <sub>oes</sub>	_	340	-	1
Total Gate Charge	V <sub>CE</sub> = 600 V, I <sub>C</sub> = 80 A, V <sub>GE</sub> = +15 V	$Q_{g}$	=	800	-	nC
Thermal Resistance - chip-to-heatsink	Thermal grease, Thickness = 76 $\mu$ m $\pm$ 2%, $\lambda$ = 2.9 W/mK	R <sub>thJH</sub>	-	0.60	-	°C/W
NEUTRAL POINT DIODE CHARACTERIST	rics					
Diode Forward Voltage	I <sub>F</sub> = 60 A, T <sub>J</sub> = 25°C	V <sub>F</sub>	=	1.7	2.2	V
	I <sub>F</sub> = 60 A, T <sub>J</sub> = 150°C	-	=	1.6	_	1
Reverse Recovery Time	T <sub>J</sub> = 25°C	t <sub>rr</sub>	=	39	-	ns
Reverse Recovery Charge	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$	Q <sub>rr</sub>	-	1.1	1	μC
Peak Reverse Recovery Current	$V_{GE} = \pm 15 \text{ V}, R_{G} = 4.7 \Omega$	I <sub>RRM</sub>	=	48	-	Α
Peak Rate of Fall of Recovery Current	7	di/dt	=	3400	-	A/μs
Reverse Recovery Energy	7	E <sub>rr</sub>	-	400	-	μЈ
Reverse Recovery Time	T <sub>J</sub> = 125°C	t <sub>rr</sub>	=	78	-	ns
Reverse Recovery Charge	$V_{CE} = 350 \text{ V}, I_{C} = 60 \text{ A}$	$Q_{rr}$	=	2.0	-	μC
Peak Reverse Recovery Current	$V_{GE}$ = ±15 V, $R_{G}$ = 4.7 $\Omega$	I <sub>RRM</sub>	-	59	-	Α
Peak Rate of Fall of Recovery Current		di/dt	_	1600	-	A/μs
Reverse Recovery Energy	_	E <sub>rr</sub>	-	550	=	μJ
Thermal Resistance - chip-to-heatsink	Thermal grease, Thickness = 76 $\mu$ m $\pm$ 2%, $\lambda$ = 2.9 W/mK	R <sub>thJH</sub>	-	1.50	_	°C/W
NEUTRAL POINT IGBT CHARACTERISTIC	cs					
Collector-Emitter Cutoff Current	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V	I <sub>CES</sub>	_	-	250	μΑ
Collector-Emitter Saturation Voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 50 A, T <sub>J</sub> = 25°C	V <sub>CE(sat)</sub>	_	1.40	1.75	V
	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 50 A, T <sub>J</sub> = 150°C	-	=	1.50	_	1
Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 1.2$ mA	V <sub>GE(TH)</sub>	-	5.45	6.4	V
Gate Leakage Current			_	_	200	nA

Table 3. ELECTRICAL CHARACTERISTICS  $T_J = 25^{\circ}C$  unless otherwise noted

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
NEUTRAL POINT IGBT CHARACTERISTI	cs					
Turn-on Delay Time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	=	30	_	ns
Rise Time	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$ $V_{GE} = \pm 15 \text{ V, } R_{G} = 4.7 \Omega$	t <sub>r</sub>	=	19	=	1
Turn-off Delay Time	- VGE - ±13 V, NG - 4.7 S2	t <sub>d(off)</sub>	=	110	=	1
Fall Time		t <sub>f</sub>	_	23	_	-
Turn-on Switching Loss per Pulse		E <sub>on</sub>	-	800	_	μJ
Turn off Switching Loss per Pulse		E <sub>off</sub>	_	480	_	1
Turn-on Delay Time	T <sub>J</sub> = 125°C	t <sub>d(on)</sub>	_	32	_	ns
Rise Time	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$	t <sub>r</sub>	_	18	_	
Turn-off Delay Time	$V_{GE}$ = ±15 V, $R_{G}$ = 4.7 $\Omega$	t <sub>d(off)</sub>	=	120		1
Fall Time		t <sub>f</sub>	_	35	_	1
Turn-on Switching Loss per Pulse	1	E <sub>on</sub>	_	1100	_	μJ
Turn off Switching Loss per Pulse	-	E <sub>off</sub>	=	880	_	1
Input Capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 10 kHz	C <sub>ies</sub>	_	9400	_	pF
Output Capacitance	- VCE - 20 V, VGE - 0 V, I - 10 KIZ	C <sub>oes</sub>		280	_	۲,
Reverse Transfer Capacitance	-	C <sub>res</sub>		250	_	1
Total Gate Charge	V <sub>CE</sub> = 480 V, I <sub>C</sub> = 50 A, V <sub>GE</sub> = +15 V	Qg	=	395	_	nC
Thermal Resistance – chip-to-heatsink	Thermal grease,	R <sub>thJH</sub>	=	1.10	_	°C/W
· ·	Thickness = 76 $\mu$ m $\pm 2\%$ , $\lambda$ = 2.9 W/mK	uiori				
HALF BRIDGE DIODE CHARACTERISTIC	S .					
Diode Forward Voltage	I <sub>F</sub> = 40 A, T <sub>J</sub> = 25°C	V <sub>F</sub>	-	2.11	3.10	V
	I <sub>F</sub> = 40 A, T <sub>J</sub> = 150°C		-	1.50	_	
Reverse recovery time	T <sub>J</sub> = 25°C	t <sub>rr</sub>	_	45	_	ns
Reverse recovery charge	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$ $V_{GE} = \pm 15 \text{ V, } R_{G} = 4.7 \Omega$	Q <sub>rr</sub>	-	2.7	_	μС
Peak reverse recovery current		I <sub>RRM</sub>	-	110	_	Α
Peak rate of fall of recovery current	_	di/dt	=	7100	_	A/μs
Reverse recovery energy		E <sub>rr</sub>		1000	_	μJ
Reverse recovery time	T <sub>J</sub> = 125°C	t <sub>rr</sub>	-	185	_	ns
Reverse recovery charge	$V_{CE} = 350 \text{ V, } I_{C} = 60 \text{ A}$ $V_{GE} = \pm 15 \text{ V, } R_{G} = 4.7 \Omega$	Q <sub>rr</sub>	-	6	_	μС
Peak reverse recovery current	VGE = ±10 V, FIG = 1.7 LL	I <sub>RRM</sub>	_	150	_	Α
Peak rate of fall of recovery current		di/dt	_	5900	_	A/μs
Reverse recovery energy		E <sub>rr</sub>	_	1900	=	μJ
Thermal Resistance – chip-to-heatsink	Thermal grease, Thickness = 76 $\mu$ m $\pm 2\%$ , $\lambda$ = 2.9 W/mK	R <sub>thJH</sub>	-	1.30	-	°C/W
THERMISTOR CHARACTERISTICS						
Nominal resistance	T = 25°C	R <sub>25</sub>	=	22	_	kΩ
Nominal resistance	T = 100°C	R <sub>100</sub>	=	1486	=	Ω
Deviation of R25		ΔR/R	-5		5	%
Power dissipation		$P_{D}$	=	200	-	mW
Power dissipation constant				2	_	mW/K
B-value	B(25/50), tolerance ±3%		_	3950	_	K
B-value	B(25/100), tolerance ±3%		_	3998	_	K
· · · · · · · · · · · · · · · · · · ·						

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

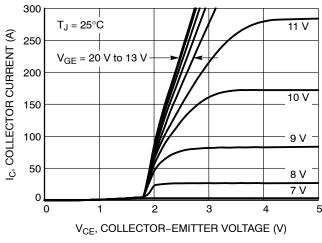
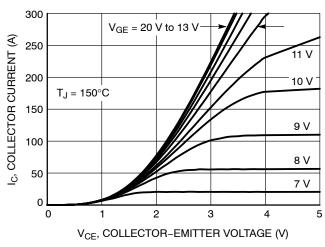


Figure 2. Typical Output Characteristics



**Figure 3. Typical Output Characteristics** 

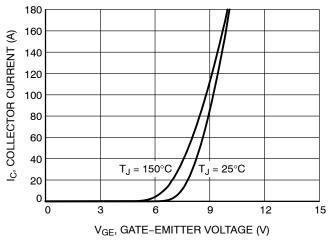


Figure 4. Typical Transfer Characteristics

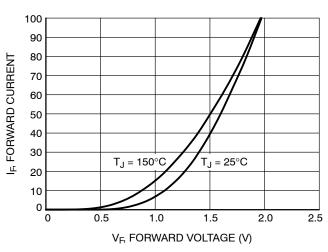


Figure 5. Diode Forward Characteristics

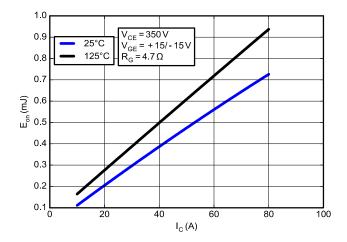


Figure 6. Typical Turn On Loss vs. IC

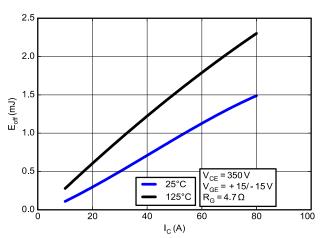
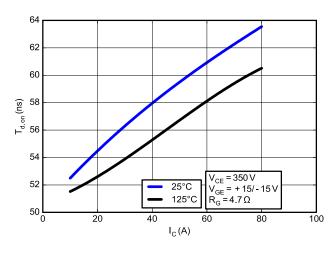


Figure 7. Typical Turn Off Loss vs. IC



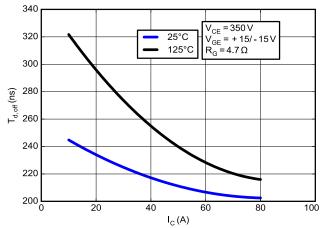
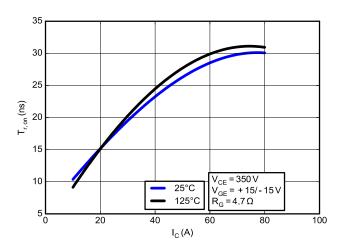


Figure 8. Typical On Switching Times vs. IC

Figure 9. Typical Off Switching Times vs. IC



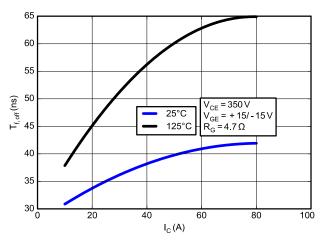
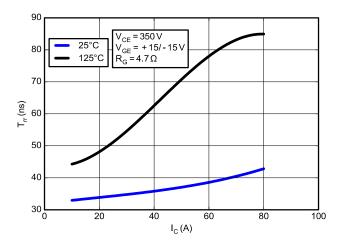


Figure 10. Typical On Rise Times vs. IC

Figure 11. Typical Off Fall Times vs. IC



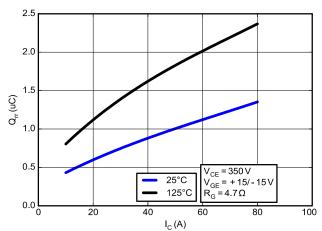
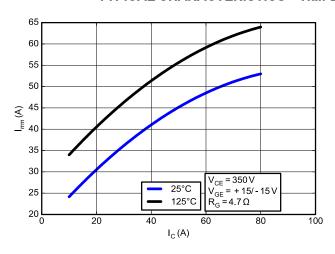


Figure 12. Typical Reverse Recovery Time vs.

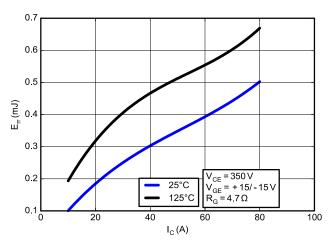
Figure 13. Typical Reverse Recovery Charge vs. IC



3500 3000 di/dt(A/µs)  $V_{CE} = 350 V$ V<sub>GE</sub> = +15/-15V 25°C 125°C  $R_G^{\circ} = 4.7\Omega$ 2000 1500 1000 L 20 40 60 80 100  $I_{C}(A)$ 

Figure 14. Typical Reverse Recovery Peak Current vs. IC

Figure 15. Typical Diode Current Slope vs. IC



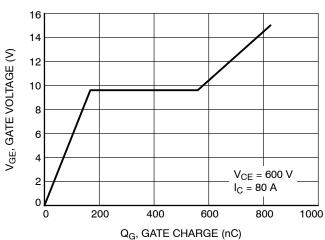


Figure 16. Typical Reverse Recovery Energy vs. IC

Figure 17. Gate Voltage vs. Gate Charge

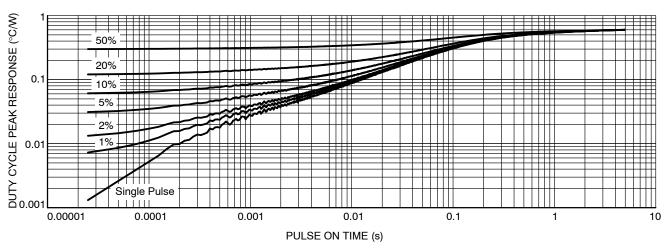


Figure 18. IGBT Transient Thermal Impedance

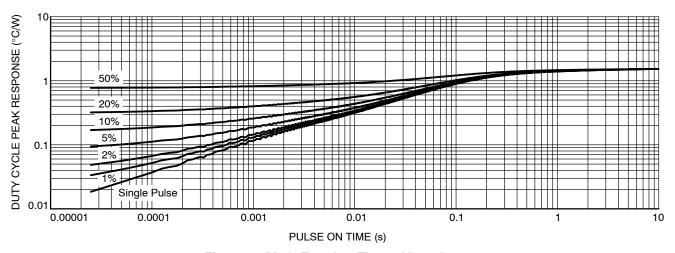


Figure 19. Diode Transient Thermal Impedance

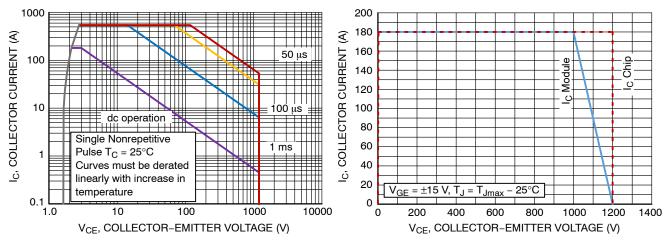


Figure 20. T1 & T4 FBSOA Figure 21. T1 & T4 RBSOA

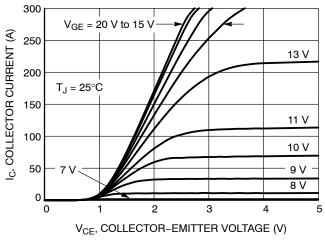


Figure 22. Typical Output Characteristics

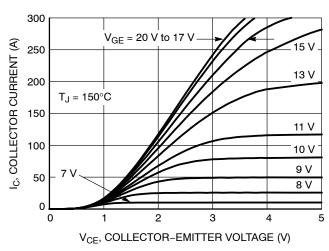


Figure 23. Typical Output Characteristics

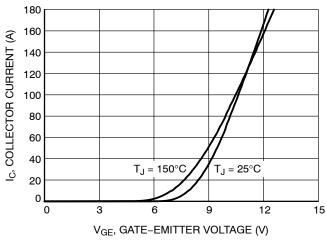


Figure 24. Typical Transfer Characteristics

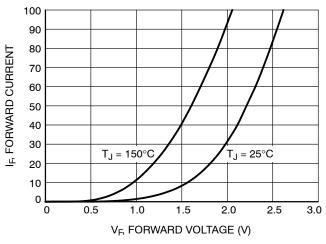


Figure 25. Diode Forward Characteristics

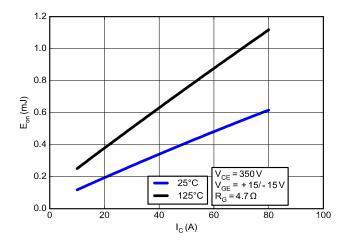


Figure 26. Typical Turn On Loss vs. IC

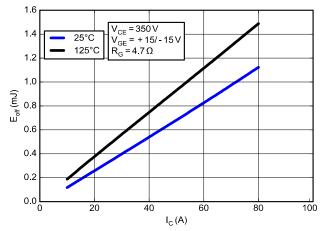
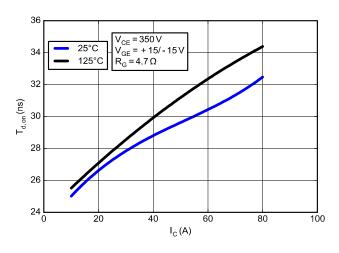


Figure 27. Typical Turn Off Loss vs. IC



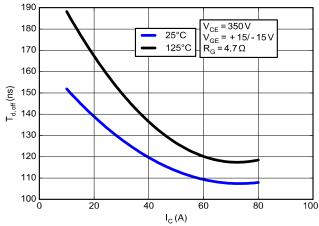
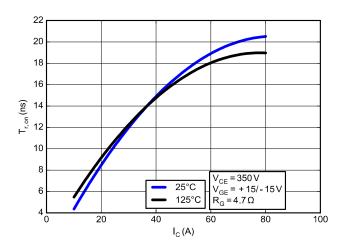


Figure 28. Typical On Switching Times vs. IC

Figure 29. Typical Off Switching Times vs. IC



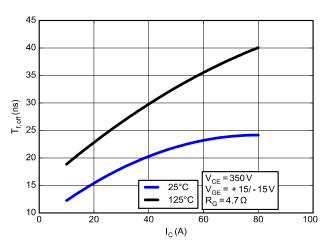
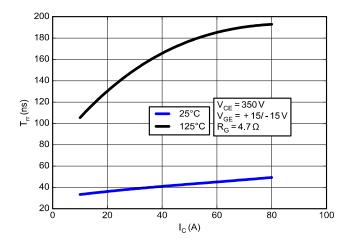


Figure 30. Typical On Rise Times vs. IC

Figure 31. Typical Off Fall Times vs. IC



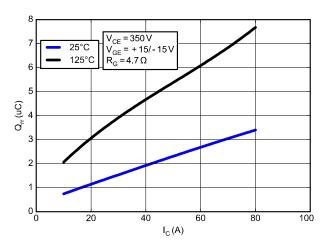
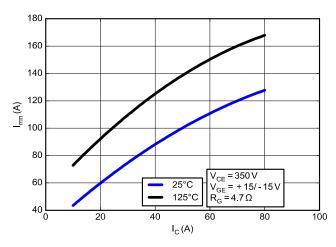


Figure 32. Typical Reverse Recovery Time vs. IC

Figure 33. Typical Reverse Recovery Charge vs. IC



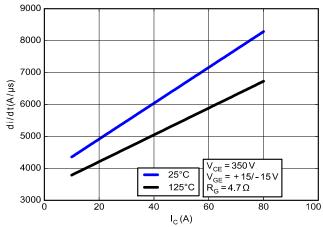
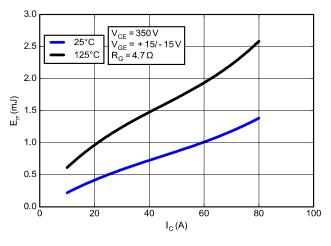


Figure 34. Typical Reverse Recovery Peak Current vs. IC

Figure 35. Typical Diode Current Slope vs. IC





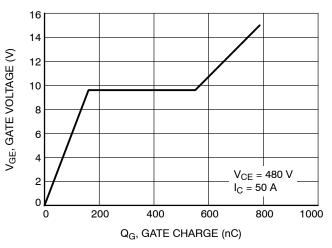


Figure 37. Gate Voltage vs. Gate Charge

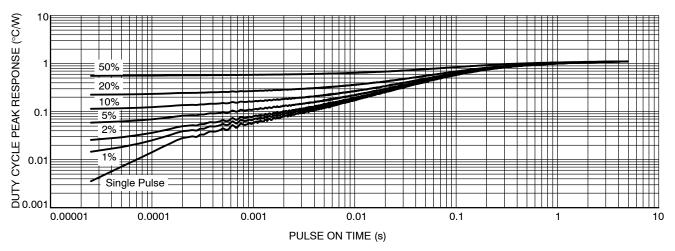


Figure 38. IGBT Transient Thermal Impedance

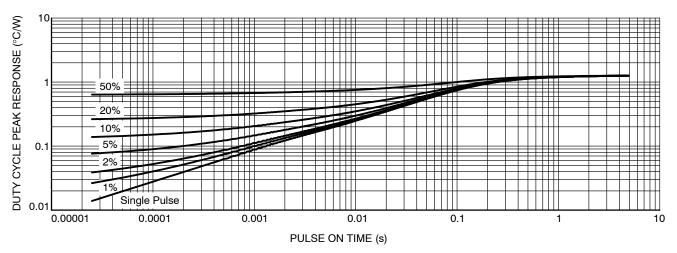


Figure 39. Diode Transient Thermal Impedance

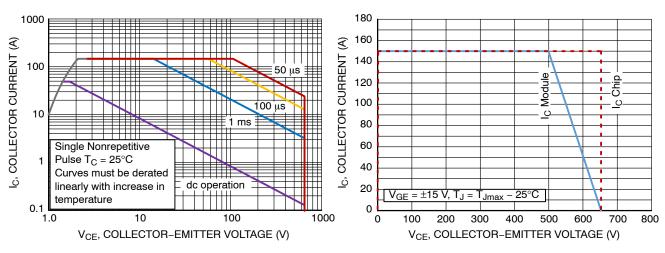


Figure 40. T2 & T3 FBSOA

Figure 41. T2 & T3 RBSOA

## **TYPICAL CHARACTERISTICS – Thermistor**

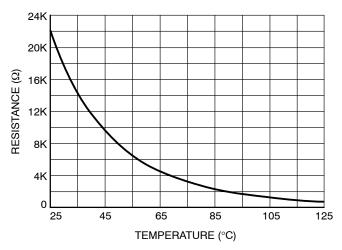


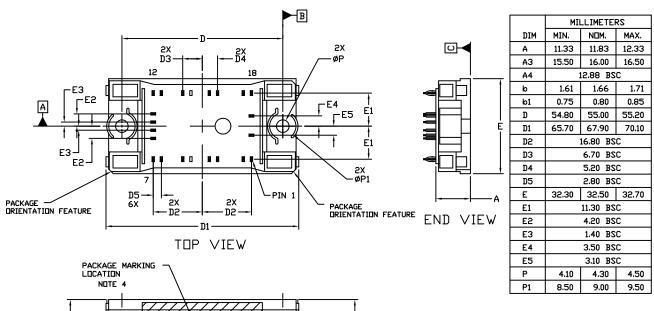
Figure 42. Thermistor Characteristics

## **ORDERING INFORMATION**

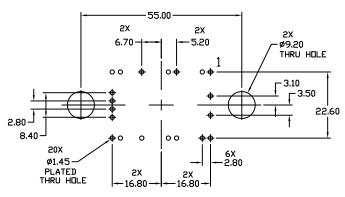
Orderable Part Number	Marking	Package	Shipping
NXH80T120L2Q0P2G	NXH80T120L2Q0P2G	Q0PACK – Case 180AA (Pb-Free and Halide-Free)	24 Units / Blister Tray
NXH80T120L2Q0S2G	NXH80T120L2Q0S2G	Q0PACK - Case 180AB (Pb-Free and Halide-Free)	24 Units / Blister Tray
NXH80T120L2Q0S2TG	NXH80T120L2Q0S2TG	Q0PACK - Case 180AB with pre-applied thermal interface material (TIM) (Pb-Free and Halide-Free)	24 Units / Blister Tray

#### PACKAGE DIMENSIONS

#### PIM20, 55x32.5 / Q0PACK CASE 180AA ISSUE D



# 20X b1 — 20X b NOTE 3 SIDE VIEW NOTE 3



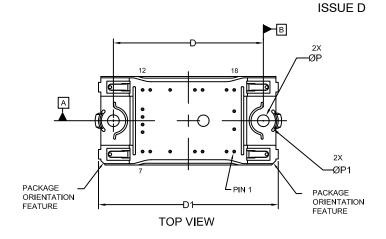
RECOMMENDED
MOUNTING PATTERN

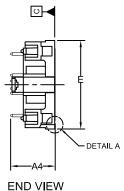
#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSIONS 6 AND 61 APPLY TO THE PLATED TERMINALS AND ARE MEASURED AT DIMENSION A4.
- 4. PACKAGE MARKING IS LOCATED AS SHOWN ON THE SIDE OPPOSITE THE PACKAGE ORIENTATION FEATURES.

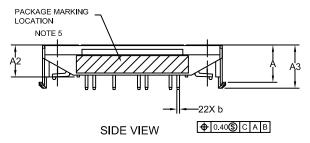
## **PACKAGE DIMENSIONS**

## PIM20, 55x32.5 / Q0PACK CASE 180AB





	MILLIMETERS			
DIM	MIN.	NOM.		
Α	13.50	13.90		
A1	0.10	0.30		
A2	11.50	11.90		
A3	15.65	16.05		
A4	16.35 REF			
b	0.95	1.05		
D	54.80	55.20		
D1	65.60	66.20		
E	32.20	32.80		
Р	4.20	4.40		
P1	8.90	9.10		





#### NOTE 4

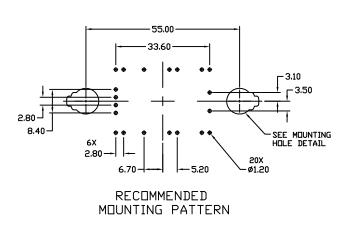
	PIN POSITION			PIN POS	SITION
PIN	Х	Υ	PIN	Х	Υ
1	16.80	-11.30	11	-16.80	4.20
2	14.00	-11.30	12	-16.80	11.30
3	5.20	-11.30	13	-14.00	11.30
4	2.40	-11.30	14	-6.70	11.30
5	-6.70	-11.30	15	2.40	11.30
6	-14.00	-11.30	16	5.20	11.30
7	-16.80	-11.30	17	14.00	11.30
8	-16.80	-4.20	18	16.80	11.30
9	-16.80	-1.40	19	16.80	3.50
10	-16.80	1.40	20	16.80	-3.10

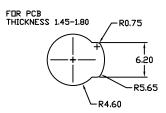
## NOTES:

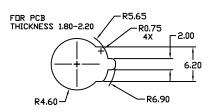
- 1. DIMENSIONING AND TOLERANCING PER. ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. DIMENSION 6 APPLIES TO THE PLATED TERMINALS AND IS MEASURED BETWEEN 1.00 AND 3.00 FROM THE TERMINAL TIP.
- 4. POSITION OF THE CENTER OF THE TERMINALS
  IS DETERMINED FROM DATUM B THE CENTER OF
  DIMENSION D, X DIRECTION, AND FROM DATUM A,
  Y DIRECTION. POSITIONAL TOLERANCE, AS NOTED
  IN DRAWING, APPLIES TO EACH TERMINAL IN BOTH
  DIRECTIONS.
- 5. PACKAGE MARKING IS LOCATED AS SHOWN ON THE SIDE OPPOSITE THE PACKAGE ORIENTATION FEATURES.

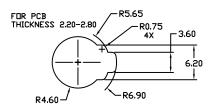
#### PACKAGE DIMENSIONS

## PIM20, 55x32.5 / Q0PACK CASE 180AB ISSUE D









MOUNTING HOLE DETAIL

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